

TEST REPORT

Report No. A-021-15-V

Date of Issue: 4 November 2015

Department of Defense Interface Standard Military Standard 461 E F

This test report is to certify that the device was tested according to the requirements of the above.
The results of this report should not be construed to imply compliance of devices other than the sample tested.
Without the laboratory approval by the documents, this report should not be copied in part.

1. Applicant

Company Name : IT Products Business Division, AVC networks company, Panasonic Corporation
Mailing Address : 1-10-12 Yagumo-higashi-machi, Moriguchi City, Osaka 570-0021, Japan

2. Identification of Tested Device

Device Name : Personal Computer
Model Number : CF-20
Serial Number : 5GKSA00273
Trade Name : Panasonic
Type of Test : Product Validation Design Validation Development Purpose
Test Plan Number : KEC-G111A_A-021-15-V Date:2015-9-25
Modification of Test Plan : No Yes (refer to deviation information in this report)

3. Test Items and Procedure

CE101	Conducted Emissions, Power Leads	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
CE102	Conducted Emissions, Power Leads	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
CS101	Conducted Susceptibility, Power Leads	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
CS106	Conducted Susceptibility, Transients, Power Leads	<input type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input checked="" type="checkbox"/> N/A (*3)
CS114	Conducted Susceptibility, Bulk Cable Injection	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
CS115	Conducted Susceptibility, Bulk Cable Injection, Impulse Excitation	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
CS116	Conducted Susceptibility, Damped Sinusoidal Transients, Cables and Power Leads	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
RE101	Radiated Emissions, Magnetic Field	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
RE102	Radiated Emissions, Electric Field	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
RS101	Radiated Susceptibility, Magnetic Field	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A
RS103	Radiated Susceptibility, Electric Field	<input checked="" type="checkbox"/> Pass	<input type="checkbox"/> Fail	<input type="checkbox"/> N/A

Refer the below reason(s) with respect to the decision and justification not to test.

(*1) DUT Specification (*2) Request of Applicant (*3) According to Test Plan (*4) Not Included in This Report

KEC Electronic Industry Development Center Testing Division
3-2-2, Hikari-dai, Seika-cho, Soraku-gun, Kyoto 619-0237 Japan

Test Engineer(s)



Hironori Okamoto



Approved by


Ikuya Minematsu / Group Manager